

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				ATTY DOCKET NO. 03560.002983		APPLICATION NO. 10/050,787	
<div style="position: relative; width: 100px; height: 100px; margin: auto;"> <div style="position: absolute; top: 0; left: 0; right: 0; bottom: 0; border: 1px solid black; border-radius: 50%; text-align: center; line-height: 100px;"> PIPE JC139 MAR 13 2002 PATENT & TRADEMARK OFFICE </div> </div>				APPLICANT TOSHIHIRO YAMASHITA ET AL..		<div style="position: relative; width: 100px; height: 100px; margin: auto;"> <div style="position: absolute; top: 0; left: 0; right: 0; bottom: 0; border: 1px solid black; border-radius: 50%; text-align: center; line-height: 100px;"> RECEIVED MAR 15 2002 GROUP NYA 1700 </div> </div>	
				FILING DATE January 18, 2002			
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
SHV	6,051,851	04/18/00	Ohmi et al.	257	185		
SHV	6,273,955	08/14/01	Yoshino et al.	118	718		
SHV	6,338,872	01/15/02	Yoshino et al.	427	248.1		
SHV	6,113,732	09/05/00	Yoshida et al.	156	345		
SHV	6,335,281	01/01/02	Segi et al.	438	680		
SHV	5,232,507	08/03/93	Ohtoshi et al.	118	719		
SHV	6,223,684	05/01/01	Fujioka et al.	118	723		
SHV	6,103,442	08/15/00	Katagiri et al.	430	127		
SHV	5,360,484	11/01/94	Takai et al.	118	723		
SHV	5,597,623	01/28/97	Takai et al.	427	575		
SHV	6,158,382	12/12/00	Segi et al.	118	723		
SHV	4,356,073	10/26/82	McKelvey	204	192 R		
SHV	4,422,916	12/27/83	McKelvey	204	192 R		
FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT	
	JP 11 029863	02/02/99	Japan			Eng. Abst.	
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
SHV	S. Schiller, et al. "Progress in the Application of the Plasma Emission Monitor in W b Coating" Pages 124-139.						
SHV	JP 11-029863 Abstract						
EXAMINER				DATE CONSIDERED			
Steven A. Ver Steeg				March 11, 2003			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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